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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): T. HIROI, et al

Serial No.: 10/079,428

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Filed: February 22, 2002

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For: APPARATUS FOR INSPECTING A SPECIMEN
Technology Center 2600

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

April 29, 2002

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

IN THE SPECIFICATION:

Page 1, in the insert Cross-Reference to Related Applications requested by the Preliminary Amendment of February 22, 2002, please amend the same as follows:

CROSS REFERENCE TO RELATED APPLICATION

This is a continuation of application Serial No. 10/062,666, filed February 5, 2002, entitled "PATTERN INSPECTION METHOD AND SYSTEM THEREFOR", by T. HIROI, the contents of which are incorporated herein by reference.

Please replace the original specification with the attached Substitute Specification.